

CONTACT ARM AND ELECTRONIC DEVICE TESTING APPARATUSUSING THE SAME

5

ABSTRACT OF THE DISCLOSURE

A contact arm for bringing ICs to be tested to contact a contact portion, comprises a holding head for holding said electronic devices, a floating
10 mechanism provided between a drive mechanism for moving close to or away from said contact portion and said holding head for supporting said holding head movable about said drive mechanism, a diaphragm
cylinder provided between said drive mechanism and
15 said holding head for adjusting a relative pressing pressure from said drive mechanism to said holding head. A plurality of diaphragm cylinders are provided to one holding head.